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April 1<sup>st</sup>, 2010 Renesas Electronics Corporation

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# R1LV1616HBG-I Series

Wide Temperature Range Version 16 M SRAM (1-Mword × 16-bit)

REJ03C0263-0100 Rev.1.00 Sep.21.2005

### **Description**

The R1LV1616HBG-I Series is 16-Mbit static RAM organized 1-Mword × 16-bit. R1LV1616HBG-I Series has realized higher density, higher performance and low power consumption by employing CMOS process technology (6-transistor memory cell). It offers low power standby power dissipation; therefore, it is suitable for battery backup systems. It is packaged in 48-ball plastic FBGA for high density surface mounting.

#### **Features**

Single 3.0 V supply: 2.7 V to 3.6 VFast access time: 45/55 ns (max)

• Power dissipation:

Active: 9 mW/MHz (typ)Standby: 1.5 μW (typ)

• Completely static memory.

- No clock or timing strobe required

• Equal access and cycle times

• Common data input and output.

- Three state output

• Battery backup operation.

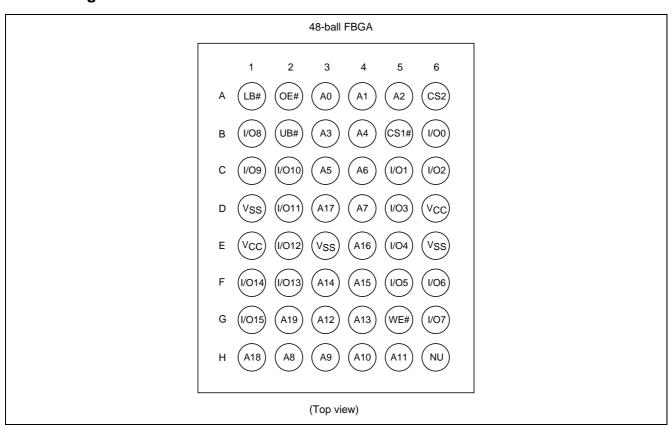
— 2 chip selection for battery backup

• Temperature range: -40 to +85°C

### **Ordering Information**

Type No.	Access time	Package
R1LV1616HBG-4SI	45 ns	48-ball plastic FBGA with 0.75 mm ball pitch
R1LV1616HBG-5SI	55 ns	PTBG0048HF (48FHJ)

### **Pin Arrangement**

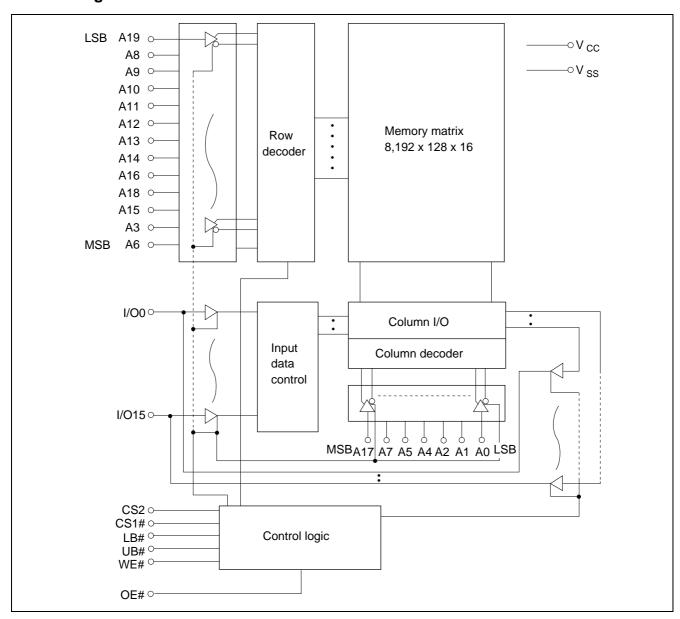


### **Pin Description**

Pin name	Function
A0 to A19	Address input
I/O0 to I/O15	Data input/output
CS1# (CS1)	Chip select 1
CS2	Chip select 2
WE# (WE)	Write enable
OE# (OE)	Output enable
LB# (\overline{LB})	Lower byte select
UB# ( <del>UB</del> )	Upper byte select
V <sub>CC</sub>	Power supply
V <sub>SS</sub>	Ground
NU* <sup>1</sup>	Not used (test mode pin)

Note: 1. This pin should be connected to a ground (V<sub>SS</sub>), or not be connected (open).

### **Block Diagram**



### **Operation Table**

CS1#	CS2	WE#	OE#	UB#	LB#	I/00 to I/07	I/O8 to I/O15	Operation
Н	×	×	×	×	×	High-Z	High-Z	Standby
×	L	×	×	×	×	High-Z	High-Z	Standby
×	×	×	×	Η	Ι	High-Z	High-Z	Standby
L	Ι	Ι	L	L	Ш	Dout	Dout	Read
L	Ι	Ι	L	Η	Ш	Dout	High-Z	Lower byte read
L	Ι	Ι	L	L	Η	High-Z	Dout	Upper byte read
L	Н	L	×	L	L	Din	Din	Write
L	Н	L	×	Н	L	Din	High-Z	Lower byte write
L	Η	Ĺ	×	L	Н	High-Z	Din	Upper byte write
L	Н	Н	Н	×	×	High-Z	High-Z	Output disable

Note: H:  $V_{IH}$ , L:  $V_{IL}$ ,  $\times$ :  $V_{IH}$  or  $V_{IL}$ 

### **Absolute Maximum Ratings**

Parameter	Symbol	Value	Unit
Power supply voltage relative to V <sub>SS</sub>	V <sub>cc</sub>	-0.5 to +4.6	V
Terminal voltage on any pin relative to V <sub>SS</sub>	V <sub>T</sub>	$-0.5*^{1}$ to $V_{CC} + 0.3*^{2}$	V
Power dissipation	P <sub>T</sub>	1.0	W
Storage temperature range	Tstg	-55 to +125	°C
Storage temperature range under bias	Tbias	-40 to +85	°C

Notes: 1.  $V_T$  min: -2.0 V for pulse half-width  $\leq 10$  ns.

2. Maximum voltage is +4.6 V.

### **DC Operating Conditions**

Parameter	Symbol	Min	Тур	Max	Unit	Note
Supply voltage	V <sub>CC</sub>	2.7	3.0	3.6	V	
	V <sub>SS</sub>	0	0	0	V	
Input high voltage	V <sub>IH</sub>	2.2	_	$V_{CC} + 0.3$	V	
Input low voltage	$V_{IL}$	-0.3	_	0.6	V	1
Ambient temperature range	Та	-40	_	+85	°C	

Note: 1.  $V_{IL}$  min: -2.0 V for pulse half-width  $\leq 10$  ns.

### **DC Characteristics**

Parameter	Symbol	Min	Тур	Max	Unit	Test conditions
Input leakage current	I <sub>LI</sub>	_	_	1	μΑ	$Vin = V_{SS}$ to $V_{CC}$
Output leakage current	I <sub>LO</sub>	_	_	1	μΑ	$CS1# = V_{IH}$ or $CS2 = V_{IL}$ or
						$OE\# = V_{IH}$ or $WE\# = V_{IL}$ or
	1			00	A	LB# = UB# = $V_{IH}$ , $V_{I/O}$ = $V_{SS}$ to $V_{CC}$
Operating current	I <sub>CC</sub>	_		20	mA	$CS1# = V_{IL}$ , $CS2 = V_{IH}$ , Others = $V_{IH}$ / $V_{IL}$ , $I_{I/O} = 0$ mA
Average operating current	I <sub>CC1</sub> (READ)	_	22* <sup>1</sup>	35	mA	Min. cycle, duty = 100%, $I_{I/O}$ = 0 mA, CS1# = $V_{IL}$ , CS2 = $V_{IH}$ , WE# = $V_{IH}$ , Others = $V_{IH}/V_{IL}$
	I <sub>CC1</sub>	_	30* <sup>1</sup>	50	mA	Min. cycle, duty = 100%, $I_{I/O}$ = 0 mA, CS1# = $V_{IL}$ , CS2 = $V_{IH}$ , Others = $V_{IH}/V_{IL}$
	I <sub>CC2</sub> (READ)	_	3* <sup>1</sup>	8	mA	Cycle time = 70 ns, duty = 100%, $I_{I/O}$ = 0 mA, CS1# = $V_{IL}$ , CS2 = $V_{IH}$ , WE# = $V_{IH}$ , Others = $V_{IH}/V_{IL}$ Address increment scan or decrement scan
	I <sub>CC2</sub>	_	20* <sup>1</sup>	30	mA	Cycle time = 70 ns, duty = 100%, $I_{I/O}$ = 0 mA, CS1# = $V_{IL}$ , CS2 = $V_{IH}$ , Others = $V_{IH}/V_{IL}$ Address increment scan or decrement scan
	I <sub>CC3</sub>	_	3* <sup>1</sup>	8	mA	Cycle time = 1 $\mu$ s, duty = 100%, $I_{I/O}$ = 0 mA, CS1# $\leq$ 0.2 V, CS2 $\geq$ V <sub>CC</sub> - 0.2 V $V_{IH} \geq$ V <sub>CC</sub> - 0.2 V, $V_{IL} \leq$ 0.2 V
Standby current	I <sub>SB</sub>	_	0.1* <sup>1</sup>	0.5	mΑ	CS2 = V <sub>IL</sub>
	I <sub>SB1</sub>	_	0.5*1	8	μА	$ \begin{array}{l} 0 \; V \leq V in \\ (1) \; 0 \; V \leq CS2 \leq 0.2 \; V \; or \\ (2) \; CS1\# \geq V_{CC} - 0.2 \; V, \\ CS2 \geq V_{CC} - 0.2 \; V \; or \\ (3) \; LB\# = UB\# \geq V_{CC} - 0.2 \; V, \\ CS2 \geq V_{CC} - 0.2 \; V, \\ CS1\# \leq 0.2 \; V \\ Average \; value \\ \end{array} $
Output high voltage	V <sub>OH</sub>	2.4	_	_	V	$I_{OH} = -1 \text{ mA}$
	V <sub>OH</sub>	V <sub>CC</sub> - 0.2	_	_	V	$I_{OH} = -100 \mu A$
Output low voltage	$V_{OL}$	_	_	0.4	V	I <sub>OL</sub> = 2 mA
	V <sub>OL</sub>	_		0.2	V	I <sub>OL</sub> = 100 μA

Notes: 1. Typical values are at  $V_{CC} = 3.0 \text{ V}$ ,  $Ta = +25^{\circ}\text{C}$  and not guaranteed.

### Capacitance

 $(Ta = +25^{\circ}C, f = 1.0 \text{ MHz})$ 

Parameter	Symbol	Min	Тур	Max	Unit	Test conditions	Note
Input capacitance	Cin	_	_	8	pF	Vin = 0 V	1
Input/output capacitance	C <sub>I/O</sub>	_	_	10	pF	$V_{I/O} = 0 V$	1

Note: 1. This parameter is sampled and not 100% tested.

#### **AC Characteristics**

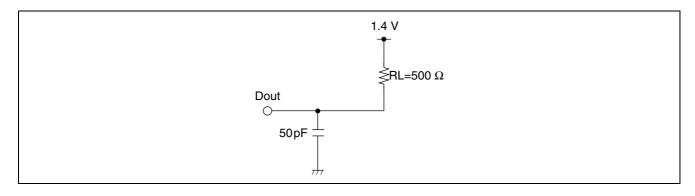
 $(Ta = -40 \text{ to } +85^{\circ}\text{C}, V_{CC} = 2.7 \text{ V to } 3.6 \text{ V})$ 

#### **Test Conditions**

• Input pulse levels:  $V_{IL} = 0.4 \text{ V}$ ,  $V_{IH} = 2.4 \text{ V}$ 

• Input rise and fall time: 5 ns

Input and output timing reference levels: 1.4 V
Output load: See figures (Including scope and jig)



#### **Read Cycle**

			R1LV16				
		-4	SI	-5	SI		
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Read cycle time	t <sub>RC</sub>	45		55		ns	
Address access time	t <sub>AA</sub>		45	_	55	ns	
Chip select access time	t <sub>ACS1</sub>		45	_	55	ns	
	t <sub>ACS2</sub>		45	_	55	ns	
Output enable to output valid	t <sub>OE</sub>	_	30	_	35	ns	
Output hold from address change	t <sub>OH</sub>	10	_	10	_	ns	
LB#, UB# access time	t <sub>BA</sub>	_	45	_	55	ns	
Chip select to output in low-Z	t <sub>CLZ1</sub>	10	_	10	_	ns	2, 3
	t <sub>CLZ2</sub>	10	_	10	_	ns	2, 3
LB#, UB# enable to low-Z	t <sub>BLZ</sub>	5	_	5	_	ns	2, 3
Output enable to output in low-Z	t <sub>OLZ</sub>	5	_	5	_	ns	2, 3
Chip deselect to output in high-Z	t <sub>CHZ1</sub>	0	20	0	20	ns	1, 2, 3
	t <sub>CHZ2</sub>	0	20	0	20	ns	1, 2, 3
LB#, UB# disable to high-Z	t <sub>BHZ</sub>	0	15	0	20	ns	1, 2, 3
Output disable to output in high-Z	t <sub>OHZ</sub>	0	15	0	20	ns	1, 2, 3

#### **Write Cycle**

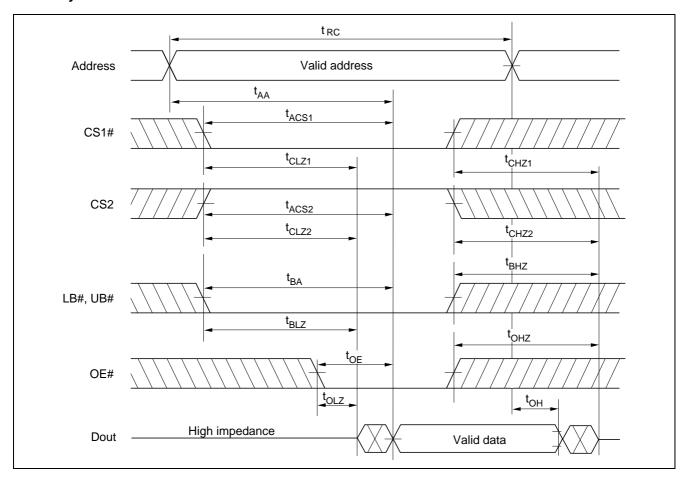
			R1LV1616HBG-I				
		-4	SI	-5	SI		
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes
Write cycle time	t <sub>WC</sub>	45		55		ns	
Address valid to end of write	t <sub>AW</sub>	45	_	50	_	ns	
Chip selection to end of write	t <sub>CW</sub>	45	_	50	_	ns	5
Write pulse width	t <sub>WP</sub>	35	_	40	_	ns	4
LB#, UB# valid to end of write	t <sub>BW</sub>	45	_	50	_	ns	
Address setup time	t <sub>AS</sub>	0	_	0	_	ns	6
Write recovery time	t <sub>WR</sub>	0	_	0	_	ns	7
Data to write time overlap	t <sub>DW</sub>	25	_	25	_	ns	
Data hold from write time	t <sub>DH</sub>	0	_	0	_	ns	
Output active from end of write	t <sub>OW</sub>	5	_	5	_	ns	2
Output disable to output in high-Z	t <sub>OHZ</sub>	0	15	0	20	ns	1, 2
Write to output in high-Z	t <sub>WHZ</sub>	0	15	0	20	ns	1, 2

Notes: 1.  $t_{CHZ}$ ,  $t_{OHZ}$ ,  $t_{WHZ}$  and  $t_{BHZ}$  are defined as the time at which the outputs achieve the open circuit conditions and are not referred to output voltage levels.

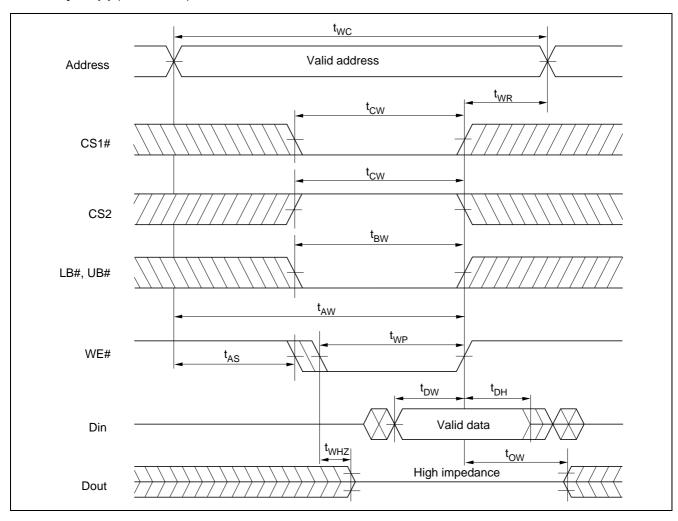
- 2. This parameter is sampled and not 100% tested.
- 3. At any given temperature and voltage condition,  $t_{HZ}$  max is less than  $t_{LZ}$  min both for a given device and from device to device.
- 4. A write occurs during the overlap of a low CS1#, a high CS2, a low WE# and a low LB# or a low UB#. A write begins at the latest transition among CS1# going low, CS2 going high, WE# going low and LB# going low or UB# going low. A write ends at the earliest transition among CS1# going high, CS2 going low, WE# going high and LB# going high or UB# going high. t<sub>WP</sub> is measured from the beginning of write to the end of write.
- 5. t<sub>CW</sub> is measured from the later of CS1# going low or CS2 going high to the end of write.
- 6. t<sub>AS</sub> is measured from the address valid to the beginning of write.
- 7.  $t_{WR}$  is measured from the earliest of CS1# or WE# going high or CS2 going low to the end of write cycle.

## **Timing Waveform**

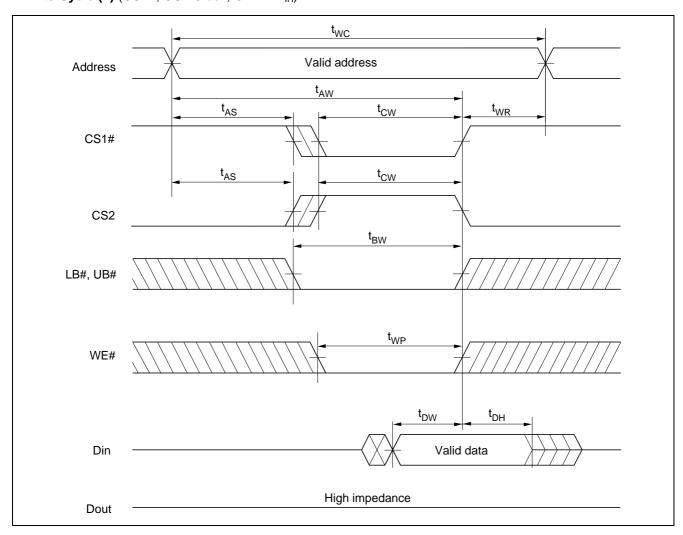
### Read Cycle



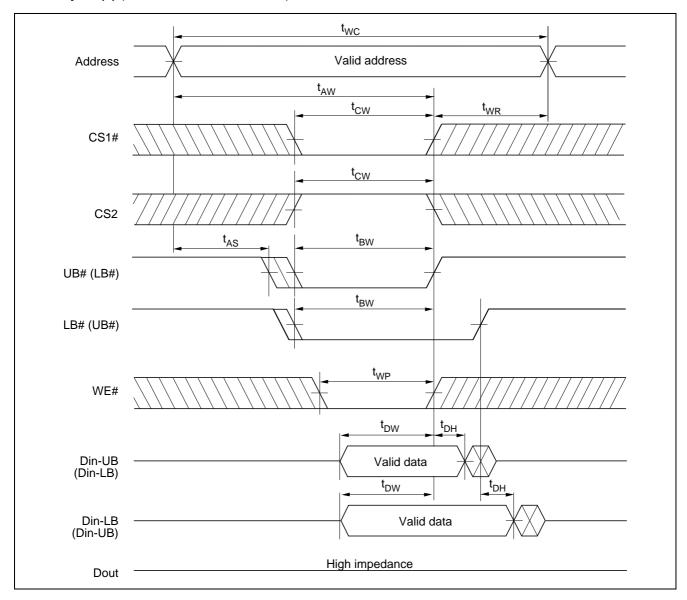
### Write Cycle (1) (WE# Clock)



### Write Cycle (2) (CS1#, CS2 Clock, OE# = $V_{IH}$ )



### Write Cycle (3) (LB#, UB# Clock, OE# = $V_{IH}$ )



### Low V<sub>CC</sub> Data Retention Characteristics

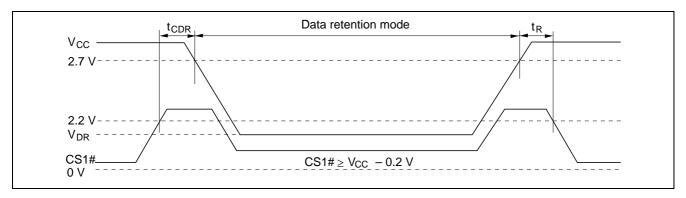
 $(Ta = -40 \text{ to } +85^{\circ}C)$ 

Parameter	Symbol	Min	Тур	Max	Unit	Test conditions* <sup>2</sup>
V <sub>CC</sub> for data retention	$V_{DR}$	1.5		3.6	V	$\begin{split} & \text{Vin} \geq 0 \text{ V} \\ & \text{(1) } 0 \text{ V} \leq \text{CS2} \leq 0.2 \text{ V or} \\ & \text{(2) } \text{CS2} \geq \text{V}_{\text{CC}} - 0.2 \text{ V}, \\ & \text{CS1\#} \geq \text{V}_{\text{CC}} - 0.2 \text{ V or} \\ & \text{(3) } \text{LB\#} = \text{UB\#} \geq \text{V}_{\text{CC}} - 0.2 \text{ V}, \\ & \text{CS2} \geq \text{V}_{\text{CC}} - 0.2 \text{ V}, \\ & \text{CS1\#} \leq 0.2 \text{ V} \end{split}$
Data retention current	I <sub>CCDR</sub>		0.5*1	æ	μА	$\begin{split} &V_{CC} = 3.0 \text{ V}, \text{ Vin } \ge 0 \text{ V} \\ &(1) \text{ 0 V } \le \text{CS2} \le 0.2 \text{ V or} \\ &(2) \text{ CS2 } \ge \text{V}_{CC} - 0.2 \text{ V}, \\ &\text{CS1\#} \ge \text{V}_{CC} - 0.2 \text{ V or} \\ &(3) \text{ LB\#} = \text{UB\#} \ge \text{V}_{CC} - 0.2 \text{ V}, \\ &\text{CS2 } \ge \text{V}_{CC} - 0.2 \text{ V}, \\ &\text{CS1\#} \le 0.2 \text{ V} \\ &\text{Average value} \end{split}$
Chip deselect to data retention time	t <sub>CDR</sub>	0	_	_	ns	See retention waveforms
Operation recovery time	t <sub>R</sub>	5	_	_	ms	

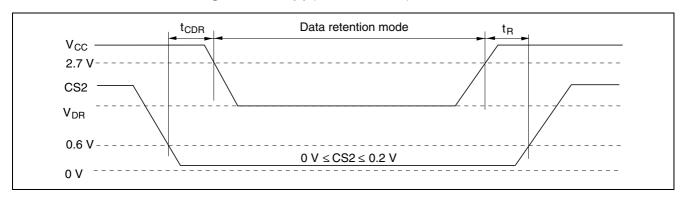
Notes: 1. Typical values are at  $V_{CC} = 3.0 \text{ V}$ ,  $Ta = +25^{\circ}C$  and not guaranteed.

<sup>2.</sup> CS2 controls address buffer, WE# buffer, CS1# buffer, OE# buffer, LB#, UB# buffer and Din buffer. If CS2 controls data retention mode, Vin levels (address, WE#, OE#, CS1#, LB#, UB#, I/O) can be in the high impedance state. If CS1# controls data retention mode, CS2 must be CS2  $\geq$  V<sub>CC</sub> - 0.2 V or 0 V  $\leq$  CS2  $\leq$  0.2 V. The other input levels (address, WE#, OE#, LB#, UB#, I/O) can be in the high impedance state.

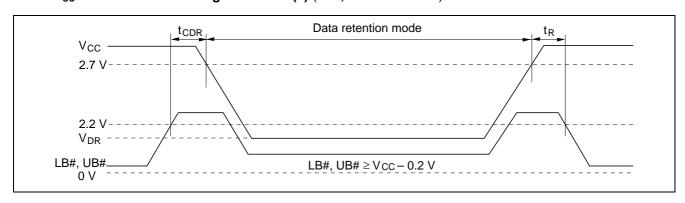
### Low V<sub>CC</sub> Data Retention Timing Waveform (1) (CS1# Controlled)



### Low V<sub>CC</sub> Data Retention Timing Waveform (2) (CS2 Controlled)



### Low V<sub>CC</sub> Data Retention Timing Waveform (3) (LB#, UB# Controlled)



### **Revision History**

### R1LV1616HBG-I Series Data Sheet

Rev.	Date		Contents of Modification			
		Page	Description			
0.01	Apr. 29. 2005	_	Initial issue			
1.00	Sep. 21. 2005	_	Deletion of Preliminary			

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